## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | INOUE ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Çlassification
	Α	US-2003/0094809	05-2003	Inoue, Tomoki	285/93
	В	US-2004/0066034	04-2004	Takayanagi et al.	285/093
	С	US-2004/0183296	09-2004	Inoue et al.	285/093
	D	US-5,354,102	10-1994	Carman, Anthony K.	285/81
	E	US-6,601,878	08-2003	Ooi et al.	285/93
	F	US-6,762,365	07-2004	Inoue et al.	174/84R
	G	US-4,035,005	07-1977	DeVincent et al.	285/319
	Н	US-3,929,357	12-1975	DeVincent et al.	285/319
	1	US-4,979,765	12-1990	Bartholomew, Donald D.	285/93
	J	US-4,135,745	01-1979	Dehar, David C.	285/319
	к	US-5,395,140	03-1995	Wiethorn, Thomas	285/93
	L	US-5,779,279	07-1998	Bartholomew, Donald D.	285/93
	М	US-5,931,509	08-1999 -	Bartholomew, Donald D.	285/93

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	ø					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	. w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.